

#### KIAT **Scalable Benchmarking Protocol for Mid-circuit Measurements**

Jaewon Jung, Jinwoo Yu, Daniel Donghyon Ohm, Minwoo Kim, JM Lee, and Eunjong Kim\*

Department of Physics and Astronomy, Seoul National University, Seoul 08858, Korea

\*E-mail: eunjongkim@snu.ac.kr



- Mid-circuit measurements (MCMs) are core building blocks for fault-tolerant quantum computing. Randomized benchmarking approach [3]





- Randomized benchmarking has the advantage of efficiency and scalable average fidelity measurements, in contrast to tomography based methods which provide detailed but non-scalable characterizations. [1-3].
- An efficient and scalable benchmarking protocol capable of characterizing and measuring the error rates of MCMs will serve as a good testbed for calibration and optimization of MCMs.



Randomized benchmarking with interleaved MCMs layers

#### Scheme 1

#### **Effectively Measurement-induced control error free**



- MCMs and single qubit gates are not performed at the same time which effectively prevents measurement-induced control errors from qubits.

#### **IBM backend results**

- On 127-qubits systems, 4-qubits are used. Number of shots = 10000
  - **1. ibm\_brisbane:** qubits = [63, 64, 65, 66]
- ZZ min w/ MCMs ZZ max w/ MCMs ZZ min w/o MCMs ZZ max w/o MCMs

for Advancement of Technology

한국산업기술진흥원

IBM Quantum





### Scheme 2

#### Measurement-induced control error added



- Mixing the gate sequences enables single qubit gates and MCMs to be overlapped so that measurement-induced control errors can be added.
- By adjusting the rate of qubit reversal to 0 or 1, state-dependent errors such as the residual ZZ interaction can be tuned.
- MCM errors are extracted using interleaved randomized benchmarking.

- Controlling the overlap between MCMs and single qubit gates is crucial.

#### Error signatures of MCMs [3]

## **Measurement induced control error**

#### Stark shift error

- $\widehat{U}_{\mathrm{Stark}} = e^{-i\phi\widehat{\sigma}_{\mathrm{z}}} \chi$ : dispersive shift.  $\bar{n}$ : mean photon number in readout resonator.  $\phi = 2\chi \bar{n}T$ *T*: measurement duration.
- $\eta$ : depolarization probability

#### Cross-measurement error

 $\widehat{K}_0 = \sqrt{p_{\rm m}} |0\rangle \langle 0|$  $p_{\rm m}$ : cross-measurement  $\widehat{K}_1 = \sqrt{p_{\rm m}} |1\rangle\langle 1|$ probability

 $\widehat{K}_2 = \sqrt{1 - p_{\rm m}}\widehat{\mathbf{I}}$ 

# $\varepsilon_{\rm dep}(\rho) = (1 - \eta)\rho + \eta \frac{1}{2}$

#### **Residual ZZ interaction**

Local measurement error

Non-QND error

 $\widehat{U}_{\rm ZZ} = e^{-i\widehat{H}_{\rm ZZ}T}$ 

 $\widehat{H}_{ZZ} = \nu |e\rangle \langle e|_{\text{measured}} \otimes \widehat{\sigma}_{z}^{\text{neighbor}}$ 

 $\nu$ : coupling rate

#### 0.0698 (0.00863)

#### 0.0494 (0.0084)

#### **MCMs** duration: **MCMs** parameters

#### 720 (720) ns **Depopulating time after MCMs: 1640 (340)** ns

# Conclusion

- Randomized benchmarking based schemes ensure scalability and efficient measurement of MCM errors.
- Adjusting the gate and MCM timing enables characterization of the error signatures of MCMs.
- Demonstration of benchmarking protocol both on a noise simulator and superconducting qubit systems-ibm\_brisbane and ibm\_osaka.

#### References

[1] K. Rudinger et al., Phys. Rev. Appl. 17, 014014 (2022). [2] J. P. Gaebler et al., Phys. Rev. A 104, 062440 (2021). [3] L. C. G. Govia et al., New Journal of Physics 25, 123016 (2023) (2020).

#### Acknowledgement

This work was supported by Korea Institute for Advancement of Technology(KIAT) grant funded by the Korea Government(Ministry of Education)(P0025681-G02P22450002201-10054408, "Semiconductor"-Specialized University). This research [4] Nielsen, Erik, et al., Quantum science and Technology 5.4, 044002 was supported by 'Quantum Information Science R&D Ecosystem Creation' through the National Research Foundation of Korea(NRF) funded by the Korean government (Ministry of Science and ICT(MSIT))(No. 2020M3H3A1110365).